

30V N-Channel Enhancement Mode MOSFET

Description

The AP30N03DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 30V$ $I_D = 60A$

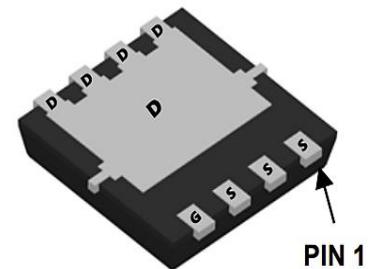
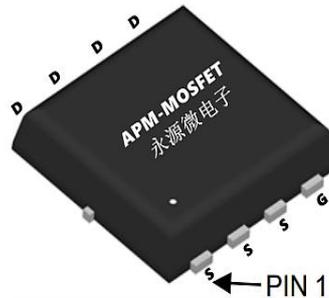
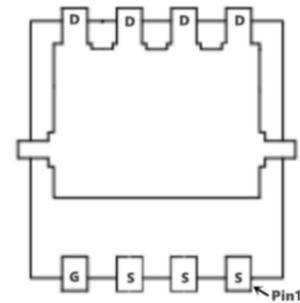
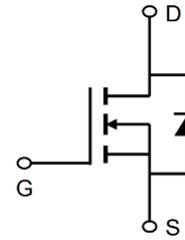
$R_{DS(ON)} < 18m\Omega$ @ $V_{GS}=10V$ (Type: 13m Ω)

Application

VBUS

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|------------|--------------------|----------|
| AP30N03DF | PDFN3*3-8L | AP30N03DF XXX YYYY | 5000 |

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|-------------------------------|--|------------|---------------------------|
| V_{DS} | Drain-Source Voltage | 30 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D @ T_C=25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 30 | A |
| $I_D @ T_C=100^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 12 | A |
| IDM | Pulsed Drain Current ² | 50 | A |
| EAS | Single Pulse Avalanche Energy ³ | 8.1 | mJ |
| IAS | Avalanche Current | 12.7 | A |
| $P_D @ T_C=25^\circ\text{C}$ | Total Power Dissipation ⁴ | 2 | W |
| TSTG | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-ambient ¹ | 85 | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 6 | $^\circ\text{C}/\text{W}$ |



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Electrical Characteristics (T_c=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------------|--|--|------|-------|------|-------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250uA | 30 | 32 | --- | V |
| ΔBVDSS/ΔT _J | BVDSS Temperature Coefficient | Reference to 25°C, I _D =1mA | --- | 0.029 | --- | V/°C |
| RDS(ON) | Static Drain-Source On-Resistance ² | V _{GS} =10V, I _D =5.8A | --- | 13 | 18 | mΩ |
| RDS(ON) | Static Drain-Source On-Resistance ² | V _{GS} =4.5V, I _D =5A | --- | 18 | 25 | |
| VGS(th) | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =250uA | 1.2 | 1.6 | 2.5 | V |
| ΔVGS(th) | VGS(th) Temperature Coefficient | | --- | -2.82 | --- | mV/°C |
| IDSS | Drain-Source Leakage Current | V _{DS} =24V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | uA |
| | | V _{DS} =24V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| IGSS | Gate-Source Leakage Current | V _{GS} =±12V, V _{DS} =0V | --- | --- | ±100 | nA |
| gfs | Forward Transconductance | V _{DS} =5V, I _D =5A | --- | 25 | --- | S |
| R _g | Gate Resistance | V _{DS} =0V, V _{GS} =0V, f=1MHz | --- | 1.5 | --- | Ω |
| Q _g | Total Gate Charge (4.5V) | V _{DS} =15V, V _{GS} =4.5V, I _D =5.8A | --- | 11.5 | --- | nC |
| Q _{gs} | Gate-Source Charge | | --- | 1.6 | --- | |
| Q _{gd} | Gate-Drain Charge | | --- | 2.9 | --- | |
| Td(on) | Turn-On Delay Time | V _{DD} =15V, V _{GS} =10V, R _G =3Ω I _D =5A | --- | 5 | --- | ns |
| T _r | Rise Time | | --- | 47. | --- | |
| Td(off) | Turn-Off Delay Time | | --- | 26 | --- | |
| T _f | Fall Time | | --- | 8 | --- | |
| C _{iss} | Input Capacitance | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 860 | --- | pF |
| C _{oss} | Output Capacitance | | --- | 84 | --- | |
| Crss | Reverse Transfer Capacitance | | --- | 70 | --- | |
| I _s | Continuous Source Current ^{1,4} | V _G =V _D =0V, Force Current | --- | --- | 5.8 | A |
| V _{SD} | Diode Forward Voltage ² | V _{GS} =0V, I _S =1A, T _J =25°C | --- | --- | 1.2 | V |

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=12.7A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

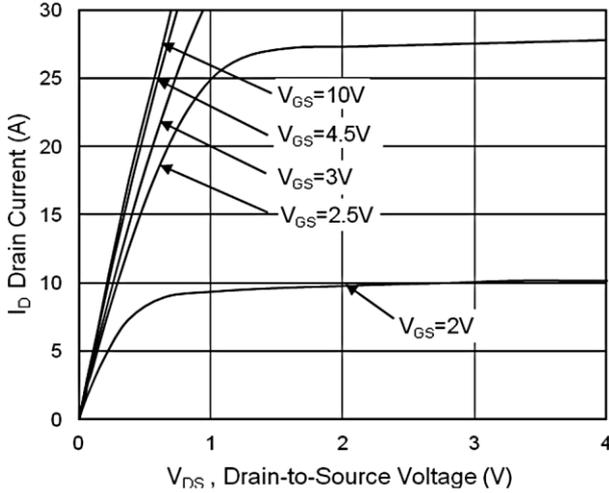


Fig.1 Typical Output Characteristics

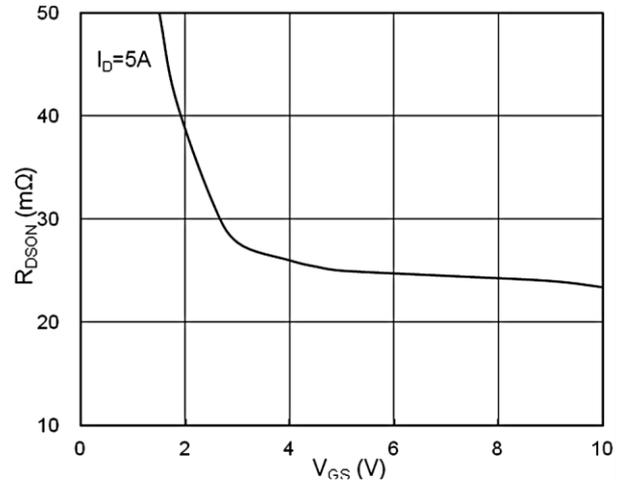


Fig.2 On-Resistance vs. Gate-Source

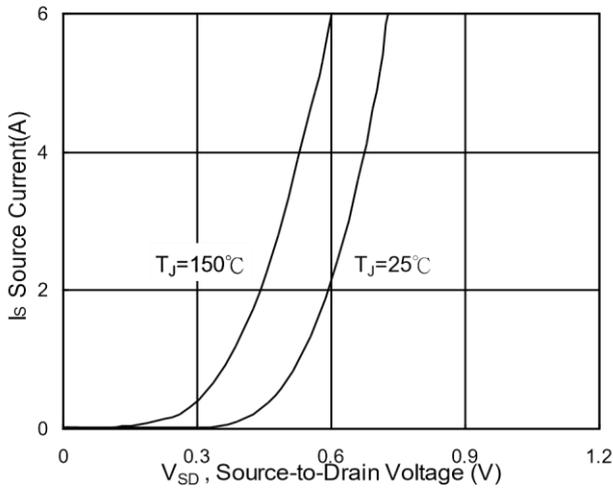


Fig.3 Forward Characteristics Of Reverse

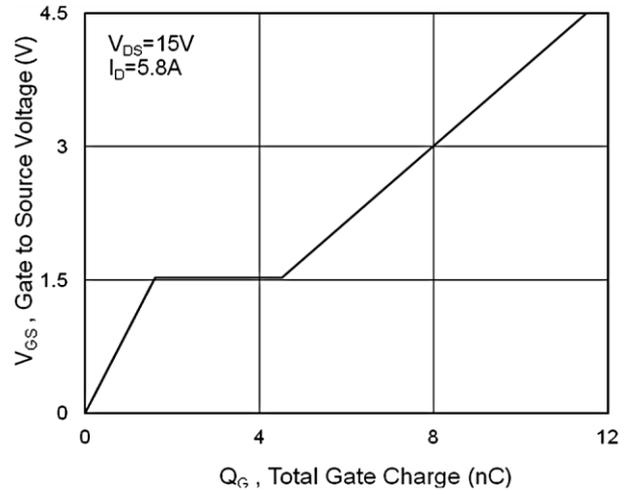


Fig.4 Gate-Charge Characteristics

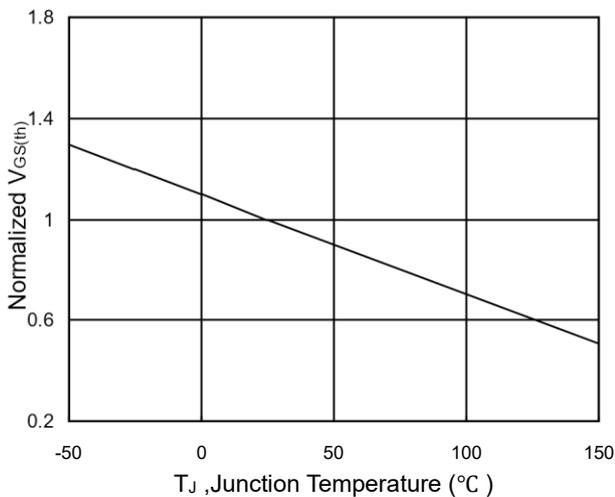


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

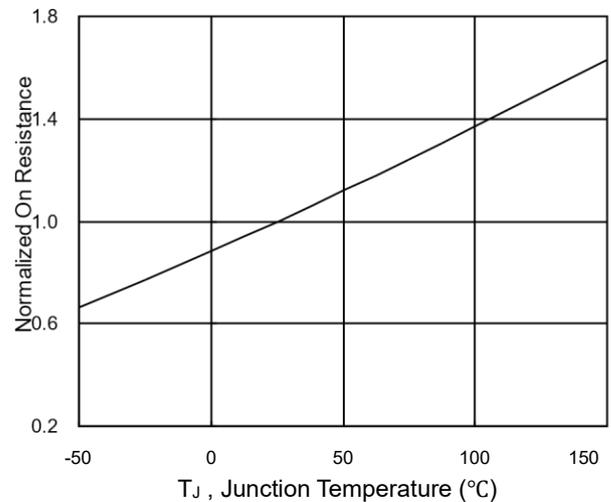


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

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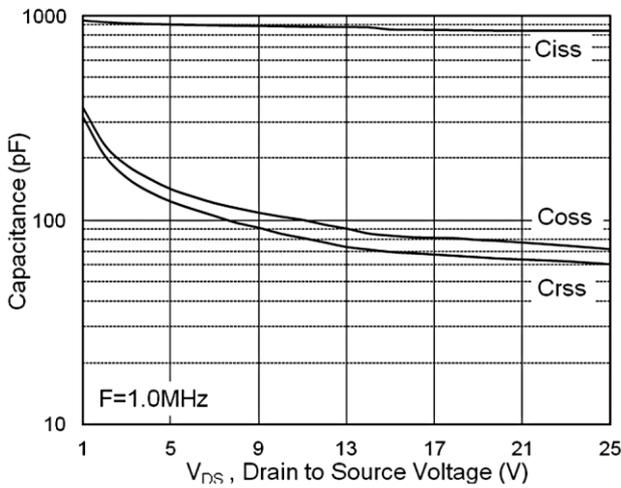


Fig.7 Capacitance

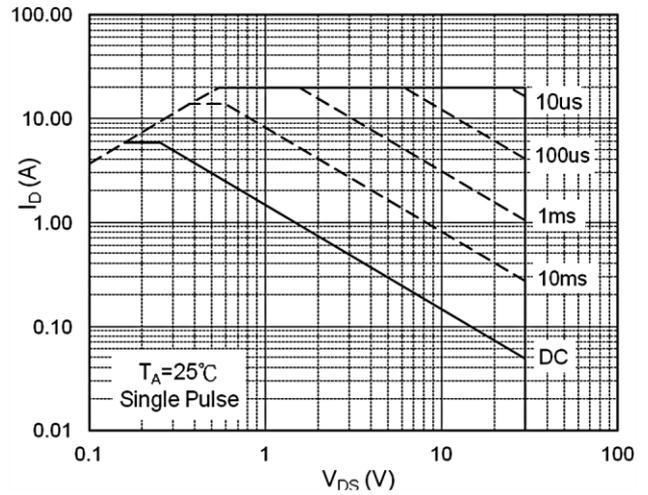


Fig.8 Safe Operating Area

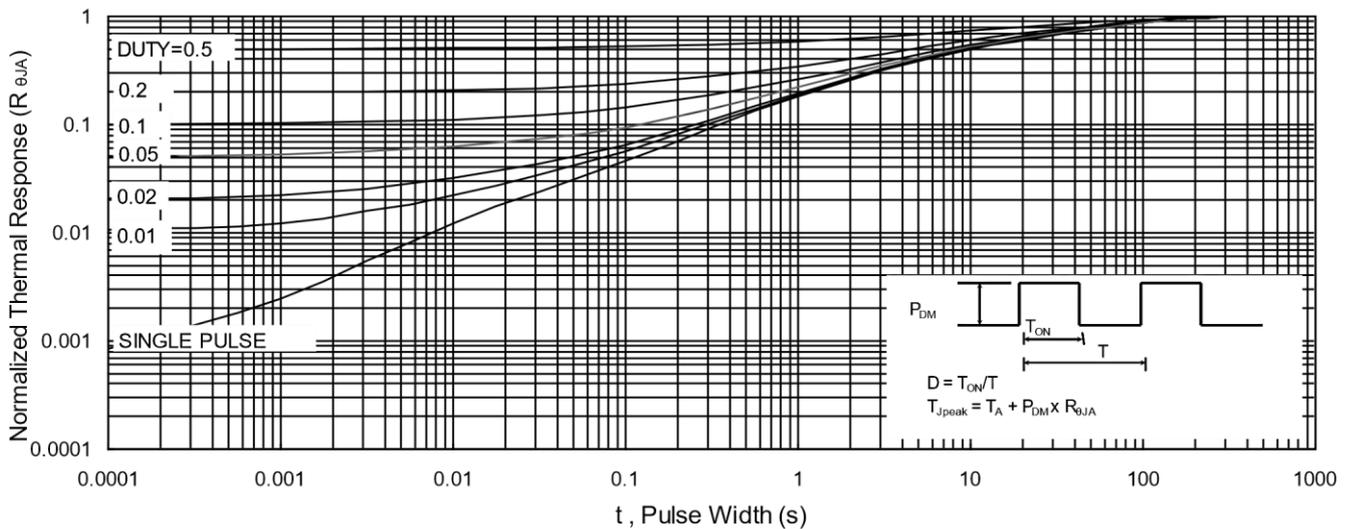


Fig.9 Normalized Maximum Transient Thermal Impedance

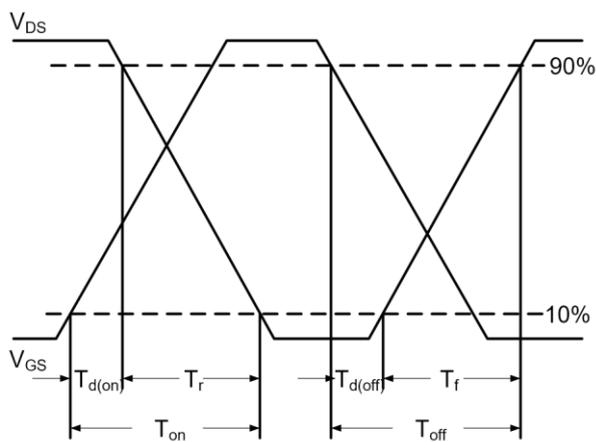


Fig.10 Switching Time Waveform

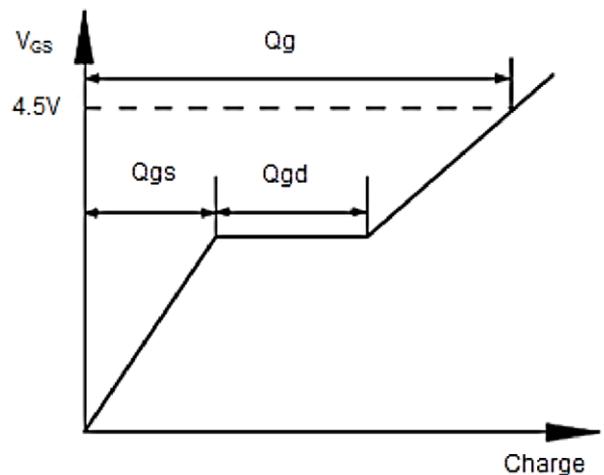
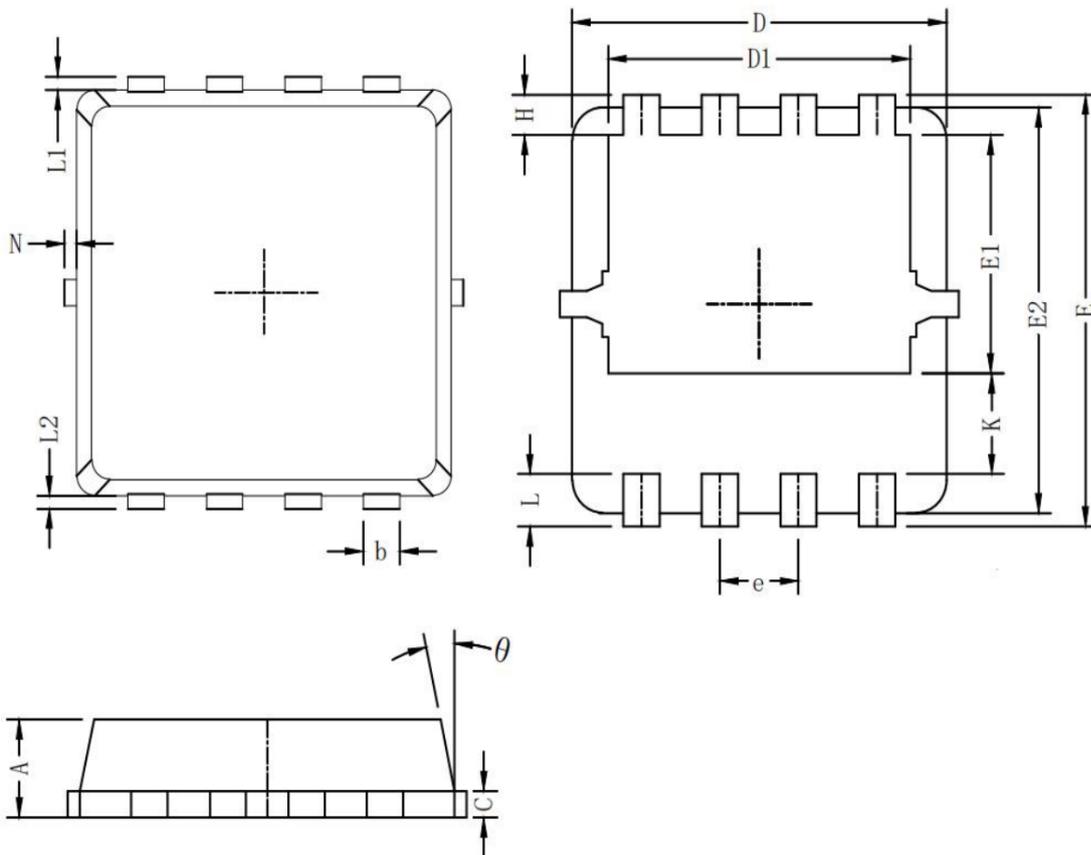


Fig.11 Gate Charge Waveform

Package Mechanical Data-PDFN3*3-8L Single



| Symbol | Dim in mm | | |
|----------|-----------|------|------|
| | min. | typ. | max. |
| A | 0.6 | 0.75 | 0.9 |
| b | 0.2 | 0.3 | 0.4 |
| C | 0.15 | 0.2 | 0.25 |
| D | 3 | 3.1 | 3.2 |
| D1 | 2.3 | 2.45 | 2.6 |
| E | 3.15 | 3.3 | 3.45 |
| E1 | 1.43 | 1.73 | 1.93 |
| E2 | 2.9 | 3.05 | 3.2 |
| e | 0.65BSC | | |
| H | 0.2 | 0.35 | 0.5 |
| K | 0.57 | 0.77 | 0.87 |
| L | 0.3 | 0.4 | 0.5 |
| L1/L2 | 0.1REF | | |
| θ | 8° | 10° | 13° |
| N | 0 | | 0.15 |

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| Edition | Date | Change |
|----------------|-------------|--------------------------------------|
| REV1.0 | 2019/4/10 | Initial release |
| REV1.1 | 2023/12/10 | Reduce internal RDS |
| REV1.2 | 2025/8/1 | Update LOGO And Corrected Manual POD |

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